

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	7	(US-20030054573-\$ or US-20040152250-\$ or US-20030096436-\$ or US-20060142971-\$ or US-20060105475-\$).did. or (US-6545752-\$ or US-5787190-\$). did.	US-PGPUB;	OR	ON	2007/10/29 09:34
L2	21	(US-20060105475-\$ or US-20060142971-\$ or US-20030096436-\$ or US-20020187582-\$ or US-20070111342-\$ or US-20040152250-\$ or US-20030138978-\$ or US-20030054573-\$).did. or (US-5787190-\$ or US-6524869-\$ or US-7179661-\$ or US-6921672-\$ or US-6576923-\$ or US-6524873-\$ or US-6509197-\$ or US-5943551-\$ or US-6957154-\$ or US-6303394-\$ or US-6545752-\$ or US-6841403-\$ or US-6797526-\$).did.	US-PGPUB;	OR	ON	2007/10/29 07:52
L3	21	L2 and (analyzing or analyz\$3 or measuring) near4 (fail\$4 or defect\$3) same (wafer or chip) and (postion or location) same (defect\$3 or fail\$4) and (calculat\$4 or comput\$4) same (data or feature or defect\$3) and (group or categor\$3) and (compar\$3 or model) same defect\$3	US-PGPUB;	OR	ON	2007/10/29 08:44
L4	1	l1 and (mathematic\$4 or equation)	US-PGPUB;	OR	ON	2007/10/29 09:35
L5	1	l1 and (mathematic\$4 or equation or fourier)	US-PGPUB;	OR	ON	2007/10/29 09:35
L22	2	("6526164").PN.	US-PGPUB;	OR	OFF	2007/10/29 10:08
L23	1	l22 and (quadratic or fourier)	US-PGPUB;	OR	ON	2007/10/29 10:09

EAST Search History

S88	14451	438/5,7,10,11,14,16,17,18,22,23,24,29,31,34,35,36,128,129,130,149,484,538.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 19:29
S108	6	(US-20050029583-\$ or US-20040087114-\$).did. or (US-6855588-\$ or US-6847084-\$ or US-6645797-\$ or US-5846734-\$).did.	US-PGPUB; USPAT	OR	ON	2006/01/10 12:04
S149	15730	438/5,7,10,11,14,16,17,18,22,23,24,29,31,34,35,36,128,129,130,149,484,538.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/02 17:42
S150	188448	"438"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/02 17:42
S151	4421	700/99,100,101,102,103,104,105,106,107,108,109,110,111,112,113,114,115,116,117,118,119,120.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/02 17:42
S152	34094	438/6,10,104,107,108,109,110,111,112,113,114,118,121,122,123,128,129,135,142,145,149,151,157,176,478,184,193,195,196,197,198,200,201,202,203,206,207,209,210,211,218,237,165,248,268,343,294,308,337,353,378,401,410,5,7,11,14,16,17,18,22,23,24,29,31,34,35,36,130,484,538.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/02 17:42
S153	35612	438/6,10,104,107,108,109,110,111,112,113,114,118,121,122,123,128,129,135,142,145,149,151,157,176,478,184,193,195,196,197,198,200,201,202,203,206,207,209,210,211,218,237,165,248,268,343,294,308,337,353,378,401,410,5,7,11,14,16,17,18,22,23,24,29,31,34,35,36,130,484,538.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/19 00:06

EAST Search History

S15 4	194081	"438"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/19 00:07
S15 5	390	S154 and stack\$3 same chip and substrate same (cover or top or lid) same open\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/19 00:09
S15 6	194156	"438"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/19 13:17
S15 7	390	S156 and stack\$3 same chip and substrate same (cover or top or lid) same open\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/19 13:27
S15 8	2	("20060063286").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/19 13:28
S15 9	0	I2I and time same invariant	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/19 13:29
S16 0	0	I2I and ((time same invariant) or time-invariant)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/19 13:29
S16 1	2	S158 and ((time same invariant) or time-invariant)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/19 13:31

EAST Search History

S16 2	2	S158 and ((time same invariant) or time-invariant) and identifier	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2006/12/19 13:31
S16 3	194156	"438"/\$.ccls.	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2006/12/19 14:20
S16 4	390	S163 and stack\$3 same chip and substrate same (cover or top or lid) same open\$3	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2006/12/19 16:01
S16 5	22	(US-20050221533-\$ or US-20050001312-\$ or US-20040145054-\$ or US-20030119300-\$ or US-20030232488-\$ or US-20010021542-\$ or US-20030017648-\$).did. or (US-6962866-\$ or US-5861670-\$ or US-5899705-\$ or US-6586322-\$ or US-6190944-\$ or US-5578516-\$ or US-5286668-\$ or US-6542393-\$ or US-6444493-\$ or US-6884313-\$ or US-6800169-\$ or US-5489804-\$ or US-5468681-\$ or US-4761681-\$ or US-4660066-\$).did.	US-PGPUB; OR USPAT	ON	2007/10/29 10:08
S16 6	6	S165 and electrode	US-PGPUB; OR USPAT	ON	2006/12/19 16:00
S16 7	22	S165 and stack\$3 same chip and substrate same (cover or top or lid) same open\$3	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2006/12/19 16:01
S16 8	6	S166 and stack\$3 same chip and substrate same (cover or top or lid) same open\$3	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2006/12/19 16:01

EAST Search History

S16 9	2	("5994217").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/11 18:14
S17 0	39047	438/6,10,104,107,108,109,110,111,112,113,114,118,121,122,123,128,129,135,142,145,149,151,157,176,478,184,193,195,196,197,198,200,201,202,203,206,207,209,210,211,218,237,165,248,268,343,294,308,337,353,378,401,410,5,7,11,14,16,17,18,22,23,24,29,31,34,35,36,130,484,538.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/23 12:47
S17 1	207027	"438"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/23 12:48
S17 2	50992	"700"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/23 13:08
S17 3	376	(analyzing or analyz\$3 or measuring) near4 (fail\$4 or defect\$3) same (wafer or chip) and (postion or location) same (defect\$3 or fail\$4) and (calculat\$4 or comput\$4) same (data or feature or defect\$3) and (group or categor\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/23 14:42
S17 4	267	(analyzing or analyz\$3 or measuring) near4 (fail\$4 or defect\$3) same (wafer or chip) and (postion or location) same (defect\$3 or fail\$4) and (calculat\$4 or comput\$4) same (data or feature or defect\$3) and (group or categor\$3) and (compar\$3 or model) same defect\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/23 14:43

EAST Search History

S17 5	34	S171 and (analyzing or analyz\$3 or measuring) near4 (fail\$4 or defect\$3) same (wafer or chip) and (postion or location) same (defect\$3 or fail\$4) and (calculat\$4 or comput\$4) same (data or feature or defect\$3) and (group or categor\$3) and (compar\$3 or model) same defect\$3	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2007/10/23 15:23
S17 6	21	(US-20060105475-\$ or US-20060142971-\$ or US-20030096436-\$ or US-20020187582-\$ or US-20070111342-\$ or US-20040152250-\$ or US-20030138978-\$ or US-20030054573-\$).did. or (US-5787190-\$ or US-6524869-\$ or US-7179661-\$ or US-6921672-\$ or US-6576923-\$ or US-6524873-\$ or US-6509197-\$ or US-5943551-\$ or US-6957154-\$ or US-6303394-\$ or US-6545752-\$ or US-6841403-\$ or US-6797526-\$).did.	US-PGPUB; OR USPAT	ON	2007/10/23 15:23
S17 7	21	S176 and (analyzing or analyz\$3 or measuring) near4 (fail\$4 or defect\$3) same (wafer or chip) and (postion or location) same (defect\$3 or fail\$4) and (calculat\$4 or comput\$4) same (data or feature or defect\$3) and (group or categor\$3) and (compar\$3 or model) same defect\$3	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2007/10/23 19:08
S17 8	21	S176 and (process or history)	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2007/10/23 15:25
S17 9	4	S176 and process same history	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2007/10/23 15:25
S18 0	7	(US-20030054573-\$ or US-20040152250-\$ or US-20030096436-\$ or US-20060142971-\$ or US-20060105475-\$).did. or (US-6545752-\$ or US-5787190-\$).did.	US-PGPUB; OR USPAT	ON	2007/10/23 17:12

EAST Search History

S18 1	7	S180 and (analyzing or analyz\$3 or measuring) near4 (fail\$4 or defect\$3) same (wafer or chip) and (postion or location) same (defect\$3 or fail\$4) and (calculat\$4 or comput\$4) same (data or feature or defect\$3) and (group or categor\$3) and (compar\$3 or model) same defect\$3	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2007/10/23 19:10
S18 2	7	(US-20030054573-\$ or US-20040152250-\$ or US-20030096436-\$ or US-20060142971-\$ or US-20060105475-\$).did. or (US-6545752-\$ or US-5787190-\$). did.	US-PGPUB; OR USPAT	ON	2007/10/24 05:43
S18 3	7	S182 and (analyzing or analyz\$3 or measuring) near4 (fail\$4 or defect\$3) same (wafer or chip) and (postion or location) same (defect\$3 or fail\$4) and (calculat\$4 or comput\$4) same (data or feature or defect\$3) and (group or categor\$3) and (compar\$3 or model) same defect\$3	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2007/10/24 11:44
S18 4	7	(US-20030054573-\$ or US-20040152250-\$ or US-20030096436-\$ or US-20060142971-\$ or US-20060105475-\$).did. or (US-6545752-\$ or US-5787190-\$). did.	US-PGPUB; OR USPAT	ON	2007/10/24 11:44
S18 5	7	S184 and (analyzing or analyz\$3 or measuring) near4 (fail\$4 or defect\$3) same (wafer or chip) and (postion or location) same (defect\$3 or fail\$4) and (calculat\$4 or comput\$4) same (data or feature or defect\$3) and (group or categor\$3) and (compar\$3 or model) same defect\$3	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ON	2007/10/24 11:44
S18 6	2	(US-20030054573-\$ or US-20060105475-\$).did.	US-PGPUB OR	ON	2007/10/24 12:25
S18 7	2	S186 and defect\$3 same wafer	US-PGPUB OR	ON	2007/10/24 12:28
S18 8	2	S186 and defect\$3 same wafer and (measur\$4 or anayli\$4)	US-PGPUB OR	ON	2007/10/24 12:28
S18 9	2	S186 and defect\$3 same wafer and (measur\$4 or analy\$5)	US-PGPUB OR	ON	2007/10/24 12:30

EAST Search History

S19 0	2	S186 and defect\$3 same wafer and (measur\$4 or analy\$5) and (position or location)	US-PGPUB	OR	ON	2007/10/24 12:31
S19 1	2	S186 and defect\$3 same wafer and (measur\$4 or analy\$5 or calculat\$4) and (position or location)	US-PGPUB	OR	ON	2007/10/24 13:08
S19 2	2	S186 and defect\$3 same wafer and (measur\$4 or analy\$5 or calculat\$4) and (position or location or match\$3)	US-PGPUB	OR	ON	2007/10/24 13:13
S19 3	2	S186 and defect\$3 and (position or location or match\$3)	US-PGPUB	OR	ON	2007/10/24 13:20
S19 4	2	S186 and (process\$3 or manufactur\$4 or tool)	US-PGPUB	OR	ON	2007/10/24 13:22
S19 5	2	S186 and (process\$3 or manufactur\$4 or tool) same defect\$4	US-PGPUB	OR	ON	2007/10/24 13:23